

In the Claims

1. (Currently Amended) ~~An A test structure for performance evaluation and/or calibration of a failure analysis instrument, analysis module for incorporation in an integrated circuit, the integrated circuit structure having circuit function modules, the and an analysis module including at least one submodule test structure arranged such that analysis of the at least one submodule test structure by the failure analysis instrument provides at least one physical parameter of the integrated circuit for use in subsequent testing of the circuit function modules failure analysis instrument.~~
2. (Currently Amended) An integrated circuit for testing and/or calibrating a failure analysis instrument, the circuit comprising:
 - circuit function modules arranged to provide operating functions of the integrated circuit; and,
 - an analysis module including at least one submodule test structure arranged such that analysis of the at least one submodule test structure by the failure analysis instrument provides at least one physical parameter of the integrated circuit for use in subsequent testing of the ~~circuit function modules~~ failure analysis instrument.
3. (Currently Amended) A system ~~for testing integrated circuit functionality performance evaluation and/or calibration of a failure analysis instrument,~~ the system comprising:
 - at least one analysis tool;
 - an integrated circuit having circuit function modules arranged to provide operating functions of the integrated circuit, and an analysis module including at least one submodule test structure, wherein
 - the at least one submodule test structure is arranged such that analysis of the at least one submodule test structure by the at least one analysis tool provides at least one physical parameter of the integrated circuit for use in subsequent testing of the ~~circuit function modules by the at least one analysis tool.~~
4. (Currently Amended) The ~~analysis module test structure, integrated circuit or system of any preceding claim 1,~~ wherein the at least one submodule test structure is chosen in dependence upon the at least one analysis tool to be used in subsequent testing.

5. (Cancelled)
6. (Currently Amended) The ~~test structure analysis module, integrated circuit, system or method of any preceding claim 1~~, wherein the at least one submodule test structure includes a calibration structure.
7. (Currently Amended) The ~~test structure analysis module, integrated circuit, system or method of any preceding claim 1~~, wherein the at least one submodule test structure includes a probing structure.
8. (Currently Amended) The ~~test structure analysis module, integrated circuit, system or method of any preceding claim 1~~, wherein the at least one submodule test structure includes optical alignment means.
9. (Currently Amended) The ~~test structure analysis module, integrated circuit, system or method of any preceding claim 1~~, wherein the at least one submodule test structure is isolated from the function modules.
10. (Cancelled)
11. (Cancelled)
12. (Cancelled)
13. (Cancelled)
14. (Cancelled)
15. (New) The integrated circuit of Claim 2, wherein the at least one submodule test structure is chosen in dependence upon the at least one analysis tool to be used in subsequent testing.
16. (New) The system of Claim 3, wherein the at least one submodule test structure is chosen in dependence upon the at least one analysis tool to be used in subsequent testing.

17. (New) The integrated circuit of Claim 2, wherein the at least one submodule test structure includes a calibration structure.
18. (New) The system of Claim 3, wherein the at least one submodule test structure includes a calibration structure.
19. (New) The integrated circuit of Claim 2, wherein the at least one submodule test structure includes a probing structure.
20. (New) The system of Claim 3, wherein the at least one submodule test structure includes a probing structure.
21. (New) The integrated circuit of Claim 2, wherein the at least one submodule test structure includes optical alignment means.
22. (New) The system of Claim 3, wherein the at least one submodule test structure includes optical alignment means.
23. (New) The integrated circuit of Claim 2, wherein the at least one submodule test structure is isolated from the function modules.
24. (New) The system of Claim 3, wherein the at least one submodule test structure is isolated from the function modules.